Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/695,791	TANAKA ET AL.	
Examiner	Art Unit	
Patrick J. Lee	2878	

SEARCHED					
Class	Subclass	Date	Examiner		
250	214R, 231.13, 231.14, 231.18	3123105 4(6102 4/6105 4/11/1105	PL		
356	614, 616		PL		
341	13		PL		
33	1PT	V	PL		
250	208.1	4/12/2005	PL		
250	208.2	4/12/2005	PL		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	-L.				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
East (see attached)	3/23/2005	PL .			
Consulted w/ S. Allen	4/5/2005	PL			
East (see attached)	4/6/2005	PL			
East (see attached)	4/11/2005	PL			
East (see attached)	4/12/2005	PL			